


<b>Search Notes</b> 	<b>Application/Control No.</b> 10565770	<b>Applicant(s)/Patent Under Reexamination</b> LOEKER ET AL.
	<b>Examiner</b> Lee, Rebecca	<b>Art Unit</b> 4181

SEARCHED			
Class	Subclass	Date	Examiner
525	165	01/14/2009	/mmd/

SEARCH NOTES			
Search Notes	Date	Examiner	
Inventor's name search in eDAN and EAST			
Assignee search in EAST			
EAST search in USPAT USPGPUB USOCR EPO JPO DERWENT	01/14/2009	/mmd/	

INTERFERENCE SEARCH			
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Examiner, Art Unit 1796